

CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Datacolor Technology Suzhou

288 Shengpu Road Suzhou Jiangsu, China 215021

Fulfills the requirements of

ISO/IEC 17025:2017

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document. The current scope of accreditation can be verified at www.anab.org.

2022

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 20 February 2025 Certificate Number: AC-1759





SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

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CALIBRATION

Valid to: **February 20, 2025** Certificate Number: **AC-1759**

Photometry and Radiometry

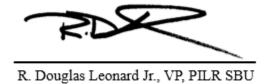
| Parameter/Equipment | Range | Expanded Uncertainty of Measurement (+/-) | Reference Standard, Method, and/or Equipment |
|--|---|---|---|
| 8°:t Geometry – Spectral Reflectance Factor | (70 to 100) %R (360 to 370) nm (380 to 390) nm (400 to 750) nm | 0.54 %R 0.44 %R 0.38 %R | CERAM Ceramic White tile, M2009 Spectrometer, JJG 453-2002 |
| 8°:d Geometry - Spectral Reflectance Factor | (70 to 100) %R (360 to 370) nm (380 to 390) nm (400 to 750) nm | 0.51 %R 0.43 %R 0.37 %R | CERAM Ceramic White tile, M2009 Spectrometer, JJG 453-2002 |
| d:0° Geometry - Spectral Reflectance Factor | (70 to 100) %R (360 to 370) nm (380 to 700) nm | 0.67 %R | CERAM Ceramic White tile, DC245 Spectrometer, JJG 453-2002 |
| Absolute 0°:45°- Bidirectional Spectral Reflectance Factor | (70 to 100) %R (400 to 410) nm (420 to 700) nm | 0.87 %R 0.79 %R | CERAM Ceramic White tile, Elrepho Spectrometer, JJG 453-2002 |

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 (*k*=2), corresponding to a confidence level of approximately 95%.

1. The uncertainty term R represents Spectral Reflectance.

Notes:

2. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-1759.



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